Computer Memory Test Labs
Intel® Approved Final Test Report

Manufacturer Name: Smart Modular Technologies
Manufacturer Part #: SH2047RD410451-SE
Module Size: 16GB
Module Config: 2048M x 72
DRAM Manufacturer: Samsung
DRAM Part #: K4A4G045WE-BCPB Rev-E
PCB Part #: M393A2G40EB1-V05
PCB Layer Count: 10 Layer
Module Info: Registered 1.2V
Assembly: JEDEC Single Board/Non Stack
Register Part: 4RCD0124KC0-ATG
Environment Code: RoHS
Low Profile: 30mm LP
Cas Latency: 15
Bank: 2

Minimum System Information
- System: S2600WT
- Serial Number: BQWS42490408
- Memory: 128GB
- Processor Code: Intel® Xeon® E5-2690 v4@ 2.60GHz
- BIOS at time of test: SE5C610.86B.01.01.0016
- Minimum System Test Status: Pass
- Maximum System Test Status: Pass

Maximum System Information
- System: S2600WT
- Serial Number: BQWS42490412
- Memory: 384GB
- Processor Code: Intel® Xeon® E5-2690 v4@ 2.60GHz
- BIOS at time of test: SE5C610.86B.01.01.0016
- Minimum System Test Status: Pass
- Maximum System Test Status: Pass

Minimum System: S2600WT
Maximum System: S2600WT

Pre-Testing Information
- Board Revision: H40442-001
- Insertion Test: Pass
- SPD Check: Pass
- Speed Check: Pass
- Power Cycle: Pass
- Voltage Margining Info
  - Volt %: VPP2.5 & VDDQ1.2
  - Volt Low: 2.42v & 1.16v
  - Volt High: 2.64v & 1.23v
- Temperature: 40°C
- Time: 12Hr

Testing Details [- Side]
- Start Date: 09/13/2016
- Stop Date: 09/15/2016
- Min IWVSS Test Status: Pass
- Max IWVSS Test Status: Pass
- SEL Min: Pass
- SEL Max: Pass
- Summary Min: Pass
- Summary Max: Pass
- Test Phase Status: Pass

Testing Details [+ Side]
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- Test Phase Status: Pass

Test Notes:
- Min configuration memory speed ran @ 2133MHz
- Mid configuration memory speed ran @ 2133MHz; memory count 256GB
- Max configuration memory speed ran @ 1600MHz

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